

Application/Control No. 10/537,830	Applicant(s)/Patent under Reexamination
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Examiner	Art Unit
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SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (see search history printout)	6/28/2007	T.D		
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